

# N-Channel 80 V (D-S) MOSFET

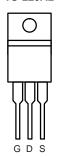
PRODUCT SUMMARY						
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω) Max.	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)			
	0.0065 at V <sub>GS</sub> = 10 V	100				
80	0.0090 at V <sub>GS</sub> = 6.0 V	90	17.1 nC			
	0.0140 at V <sub>GS</sub> = 4.5 V	70				

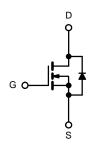
#### **FEATURES**

- TrenchFET® Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested









N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (	T <sub>A</sub> = 25 °C, unless	otherwise noted	d)		
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V <sub>DS</sub>	80	V		
Gate-Source Voltage		$V_{GS}$	± 20	V	
	T <sub>C</sub> = 25 °C		100		
Continuous Drain Current /T 150 °C)	T <sub>C</sub> = 70 °C	,	65 <sup>a</sup>		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	28.6 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		24.9 <sup>b, c</sup>	_	
Pulsed Drain Current (t = 100 μs)		I <sub>DM</sub>	350	A	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	,	100		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	4.5 <sup>b, c</sup>		
Single Pulse Avalanche Current	l 0.1 mll	I <sub>AS</sub>	30		
Single Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	45	mJ	
	T <sub>C</sub> = 25 °C		180		
Maximum Dayyar Dissination	T <sub>C</sub> = 70 °C		120	W	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	5 <sup>b, c</sup>	VV	
	T <sub>A</sub> = 70 °C		3.2 <sup>b, c</sup>		
Operating Junction and Storage Temperature R	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C		
Soldering Recommendations (Peak Temperature	_	260			

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b, f</sup>	t ≤ 10 s	$R_{thJA}$	20	25	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	1.5	2.0	C/VV	

#### **Notes**

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. The TO-220 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 70 °C/W.

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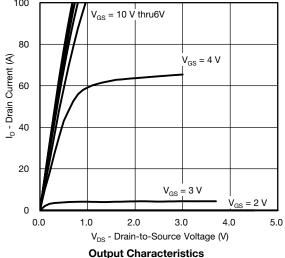
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				L			
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	80			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$			37		1400	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	— I <sub>D</sub> = 250 µA		- 6.1		mV/°C	
Gate-Source Threshold Voltage	V <sub>GS(th</sub> )	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.5		4.5	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Oala Vallana Baria Oanad		$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	85			Α	
		$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		0.0065	<del></del>		
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 6 V, I <sub>D</sub> = 15 A		0.0090		Ω	
		$V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		0.0140			
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	$V_{DS} = 10 \text{ V}, I_D = 20 \text{ A}$		60		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			5560		pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1400			
Reverse Transfer Capacitance	C <sub>rss</sub>			560			
		$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		35.5		nC	
Total Gate Charge	Q <sub>g</sub> V <sub>I</sub>	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 6 V, I <sub>D</sub> = 10 A		22			
				17.1			
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		5.3			
Gate-Drain Charge	$Q_{gd}$			7.3			
Output Charge	Q <sub>oss</sub>	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V		57	86		
Gate Resistance	$R_{g}$	f = 1 MHz	0.5	1.3	2	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			12	24		
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_L = 4 \Omega$		8	16		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong 10 \text{ Å}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		32	64	1	
Fall Time	t <sub>f</sub>			7	14		
Turn-On Delay Time	t <sub>d(on)</sub>			14	28	ns	
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_{L} = 4 \Omega$		11	22	]	
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 6.0 \text{ V}, R_g = 1 \Omega$		30	60		
Fall Time	t <sub>f</sub>			8	16		
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C		75		А	
Pulse Diode Forward Current (t = 100 μs)	I <sub>SM</sub>			150		^	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 5 A		0.76	1.1	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			38	75	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I= = 10 A dl/dt = 100 A/vo T: = 25 °C		36	70	nC	
Reverse Recovery Fall Time	ta	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 °\text{C}$		19		ne	
Reverse Recovery Rise Time	t <sub>b</sub>	t <sub>b</sub>		19		ns	

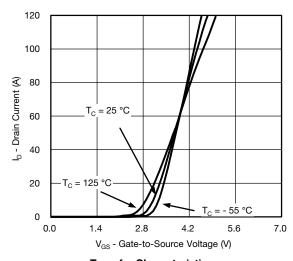
#### Notes

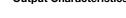
- a. Pulse test; pulse width  $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

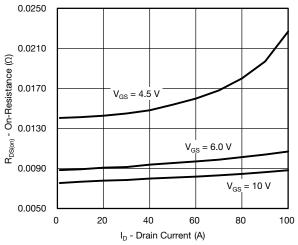
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



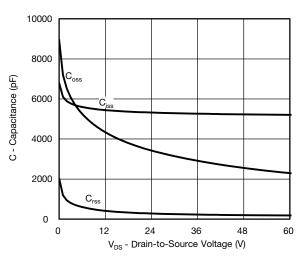




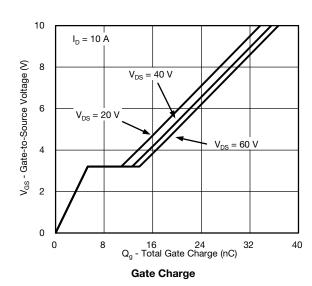




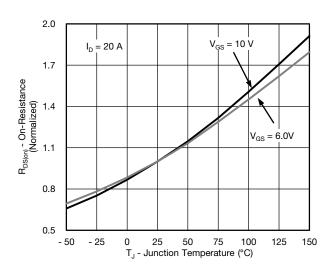




#### On-Resistance vs. Drain Current

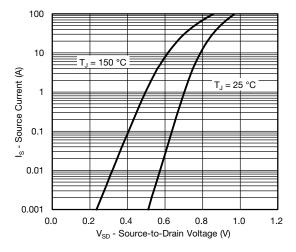


Capacitance

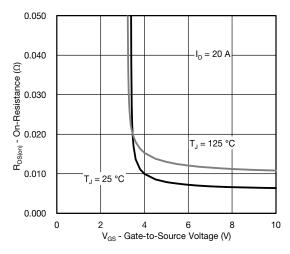


On-Resistance vs. Junction Temperature

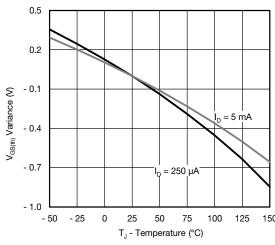




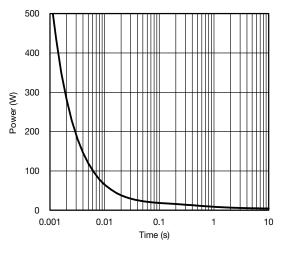
Source-Drain Diode Forward Voltage



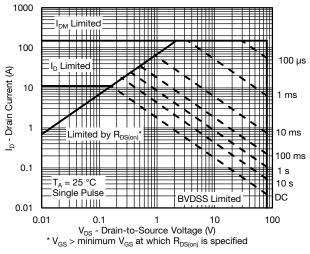
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

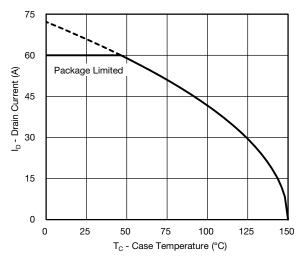


Single Pulse Power, Junction-to-Ambient

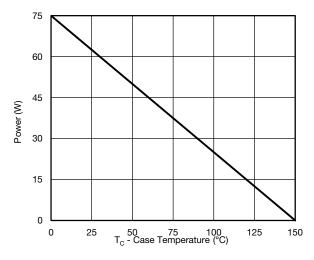


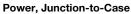
Safe Operating Area, Junction-to-Ambient

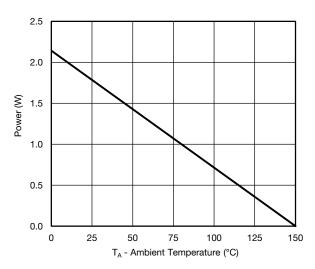




#### **Current Derating\***



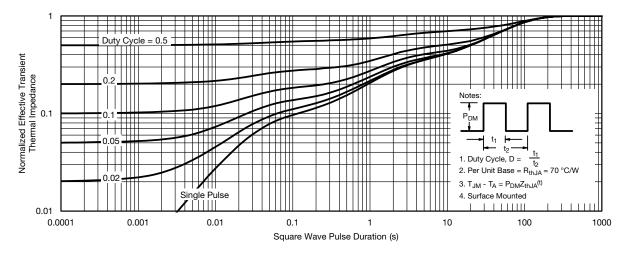




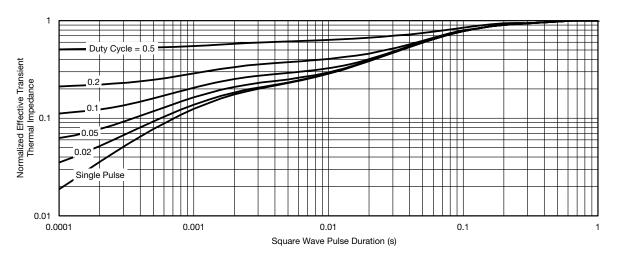
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max.)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient

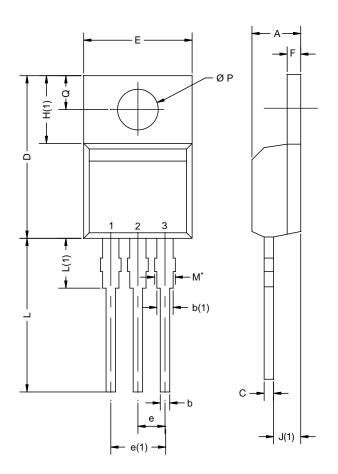


Normalized Thermal Transient Impedance, Junction-to-Case

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# **TO-220AB**



	MILLIM	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
E	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12					

# DWG: 5471

 $<sup>^{\</sup>star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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